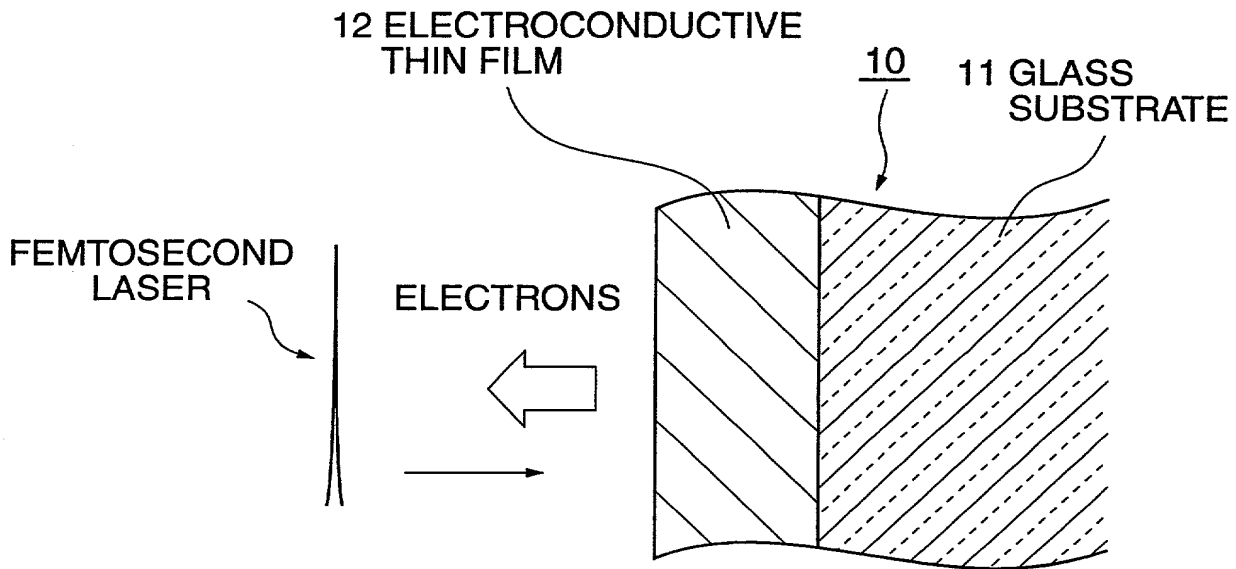
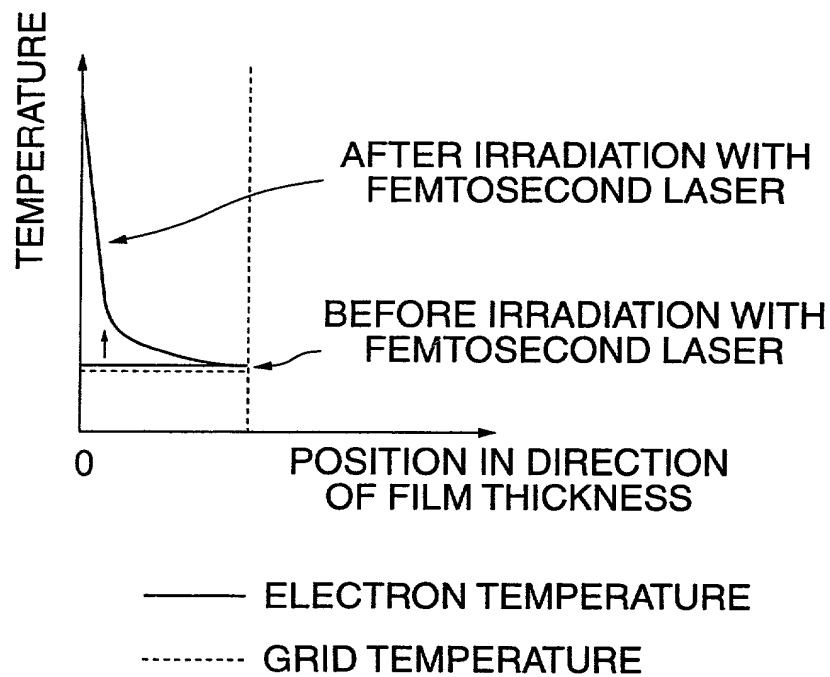
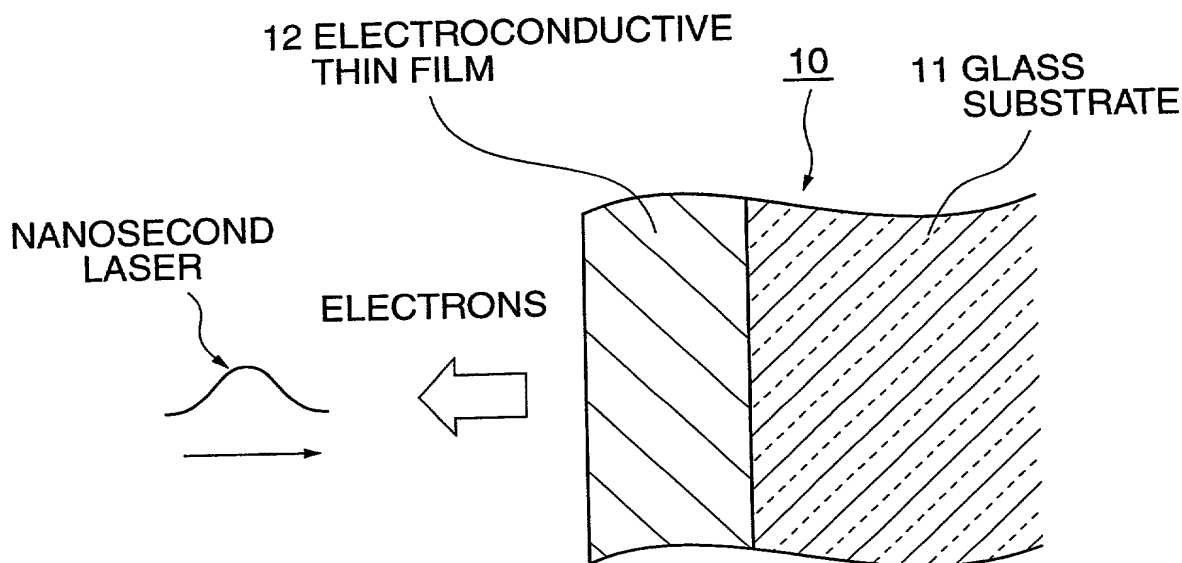
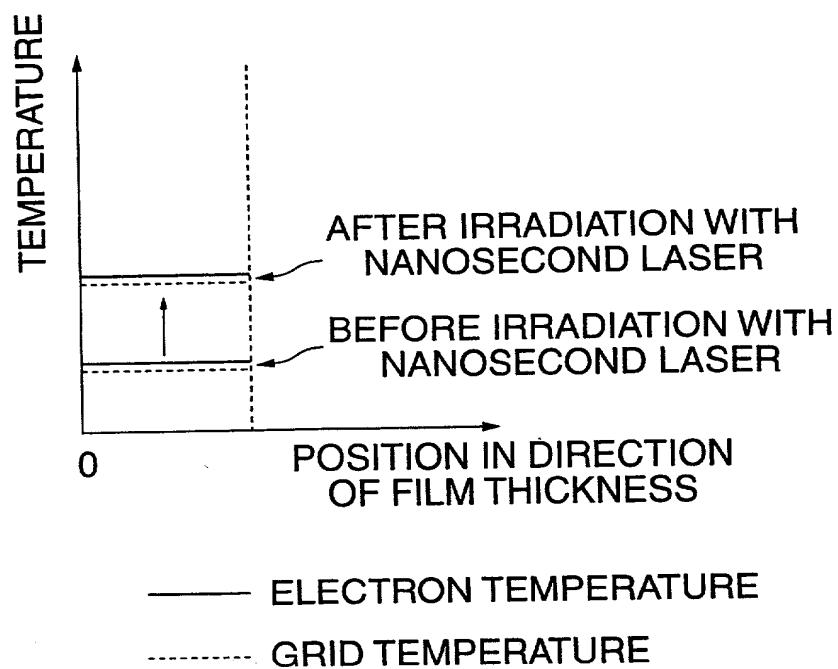


**FIG.1A**

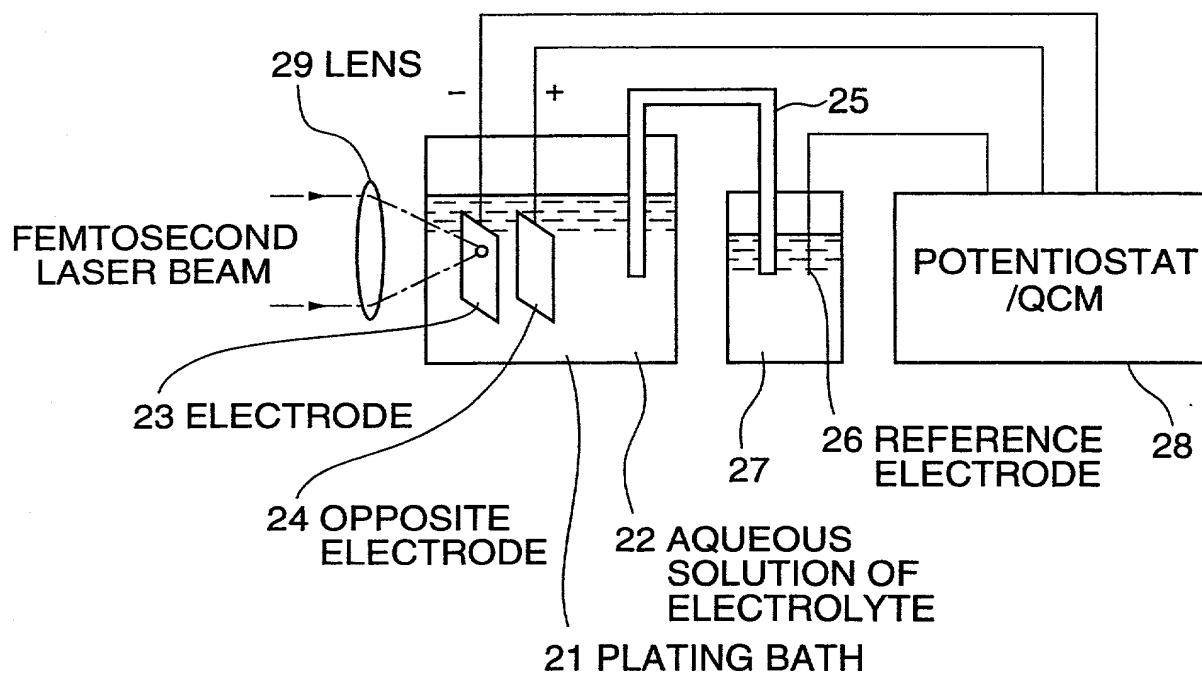


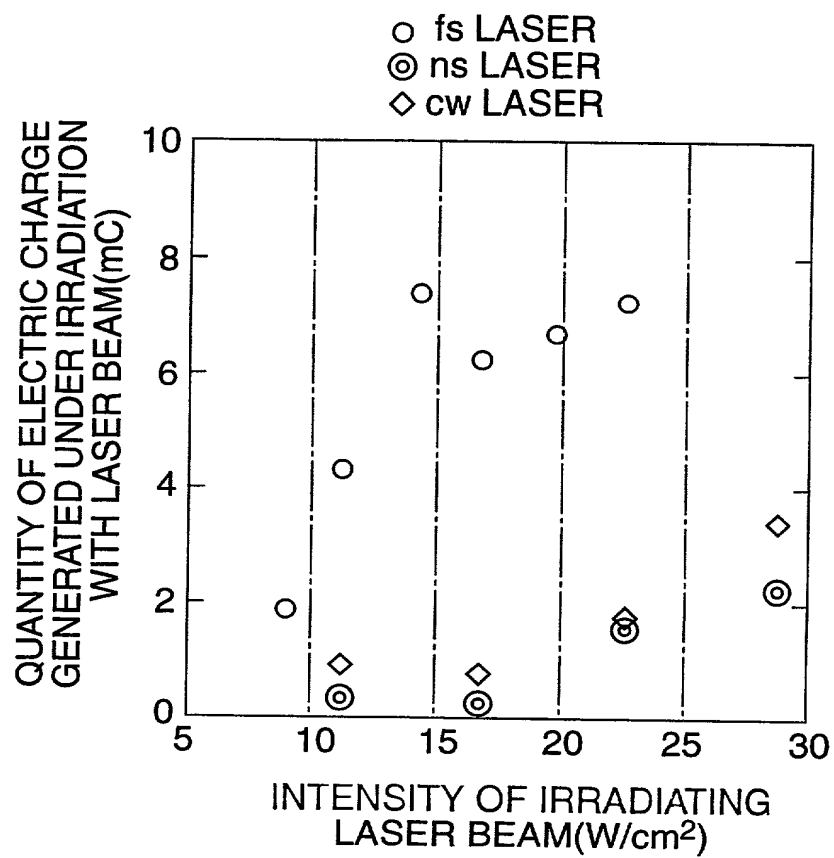
**FIG.1B**



**FIG.2A****FIG.2B**

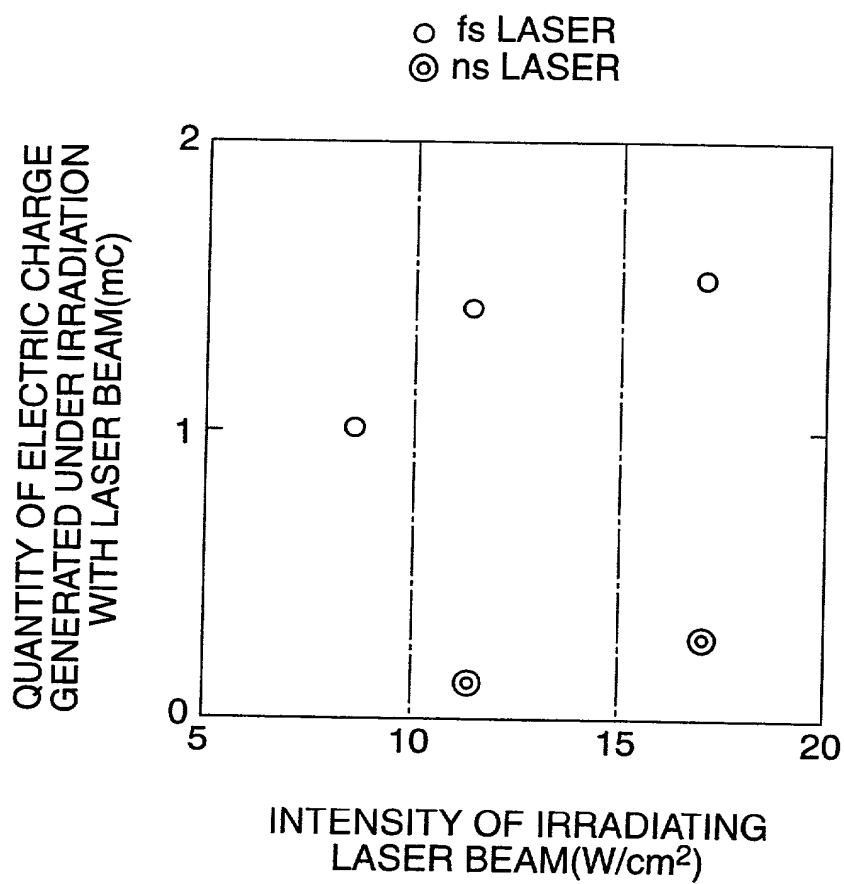
**FIG.3**



**FIG.4**

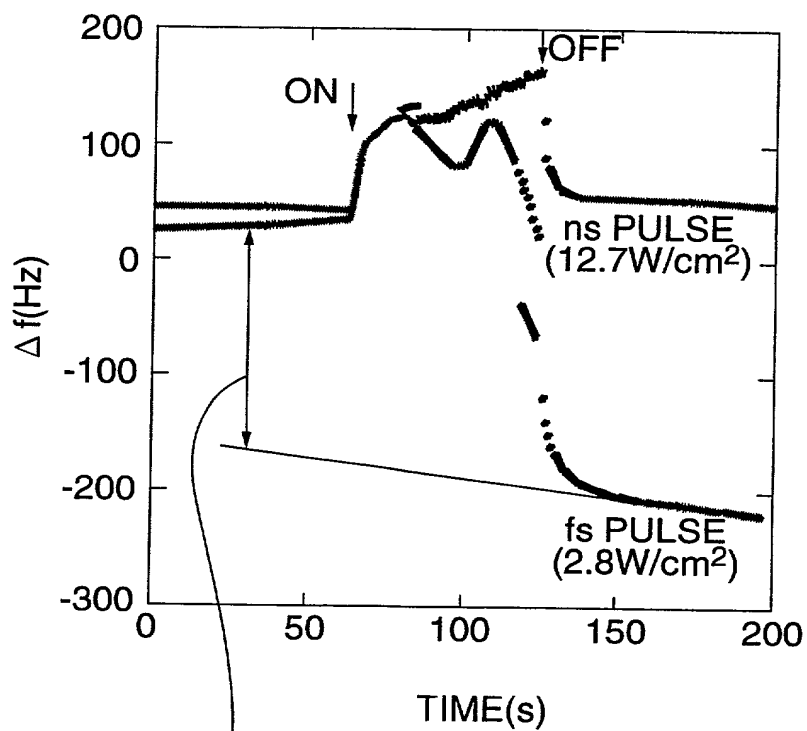
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**FIG.5**



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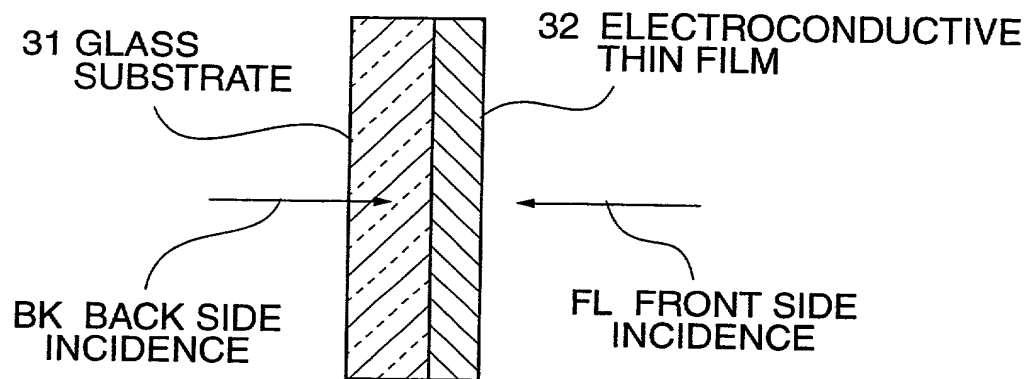
**FIG.6**



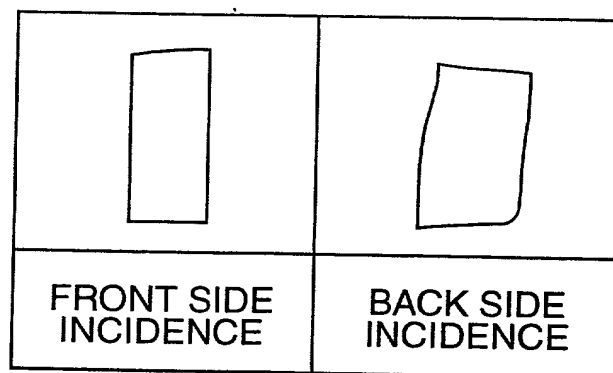
WEIGHT INCREASE  
ALONG WITH  
PLATING FORMATION

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**FIG.7**



**FIG.8**



T1: IRRADIATION WITH SAPPHIRE LASER BEAM  
(2 W/cm<sup>2</sup>, -600mV, 150s)

**FIG.9**

	Cu	Ni	O	C
fs LASER INCIDENT ON FRONT SIDE	12	12	37	39
fs LASER INCIDENT ON BACK SIDE	19	0	29	52

(atomic%)

NOTE 1) COMPOSITION MAY INVOLVE ERRORS OF  
UP TO ABOUT 30%.

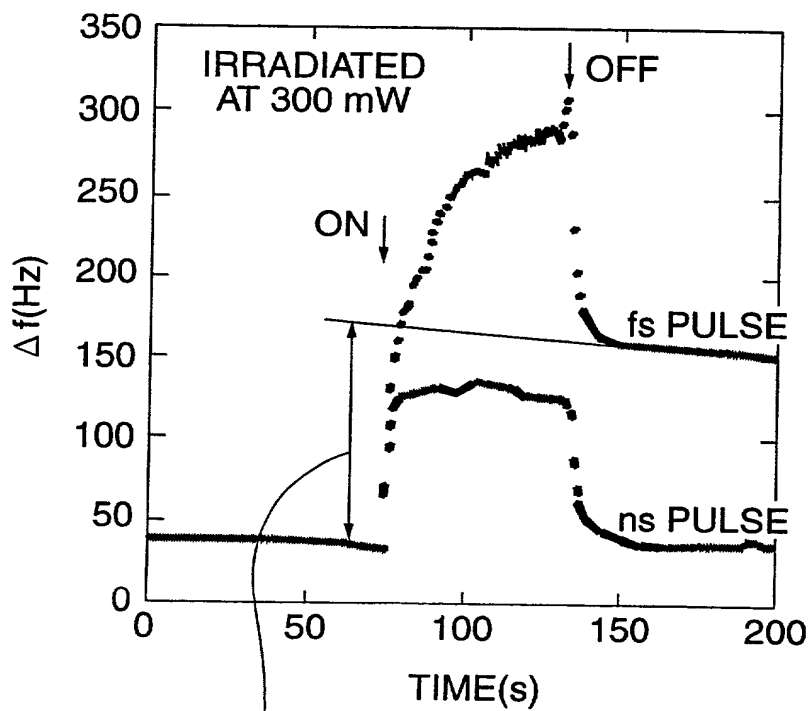
NOTE 2) ANALYSIS DEPTH OF XPS IS A FEW nm.

NOTE 3) MOST PART OF DETECTED C IS ATTRIBUTABLE TO  
HYDROCARBONS, WHICH CONTAMINATE SURFACE.



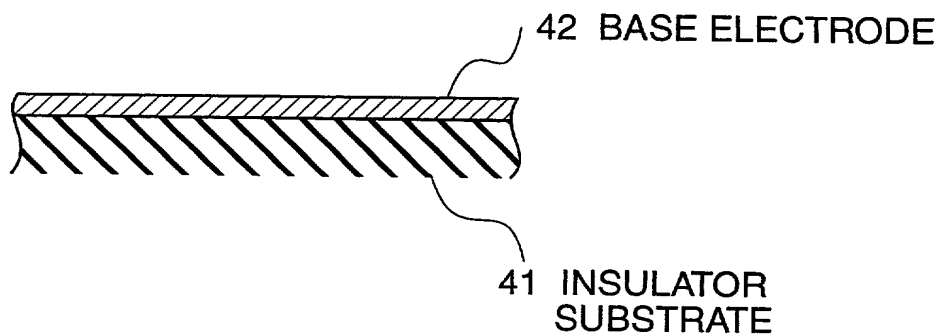
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**FIG.10**

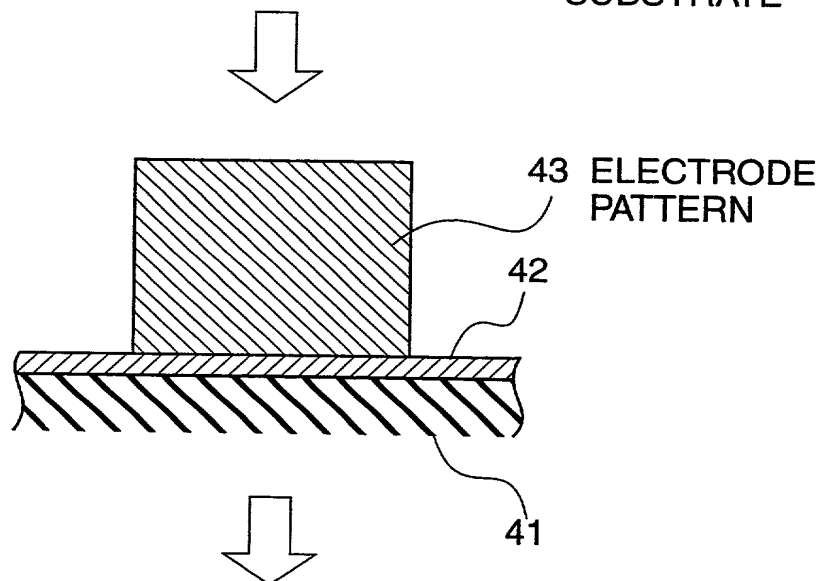


WEIGHT DECREASE  
ATTRIBUTABLE TO ETCHING

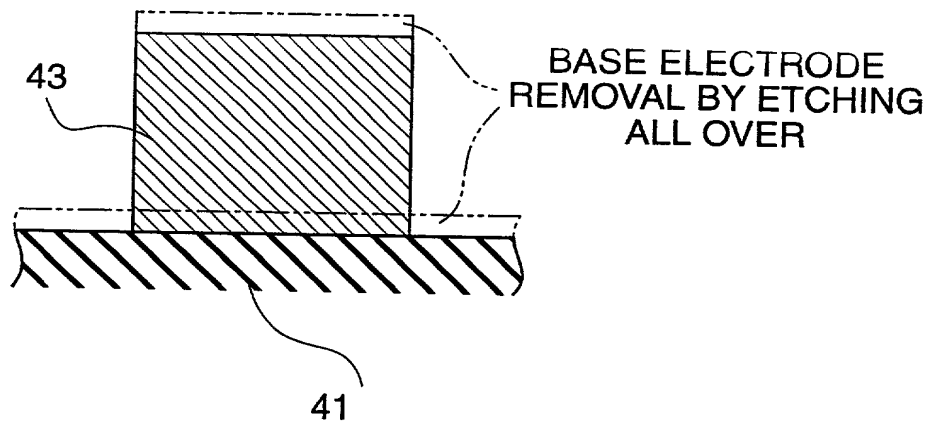
**FIG.11A**



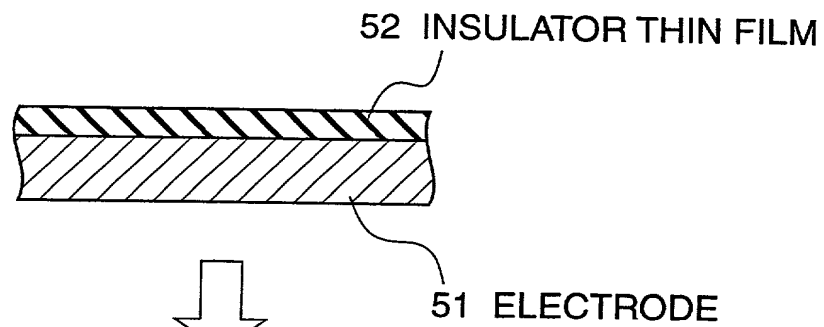
**FIG.11B**



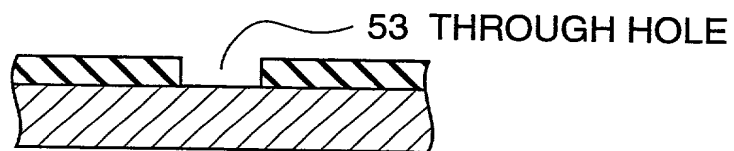
**FIG.11C**



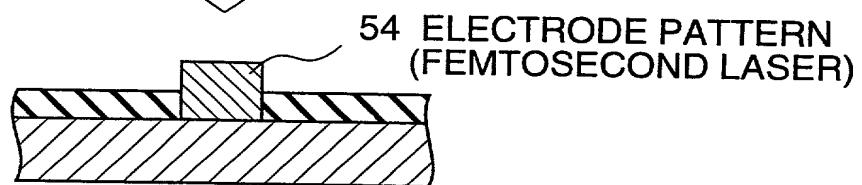
**FIG.12A**



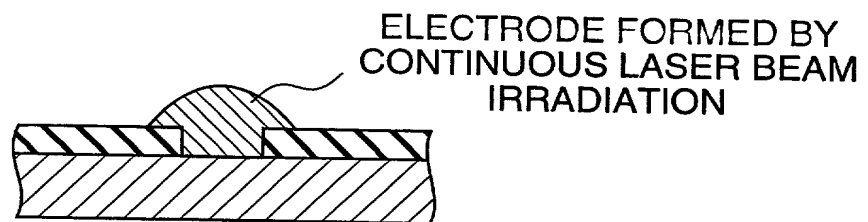
**FIG.12B**



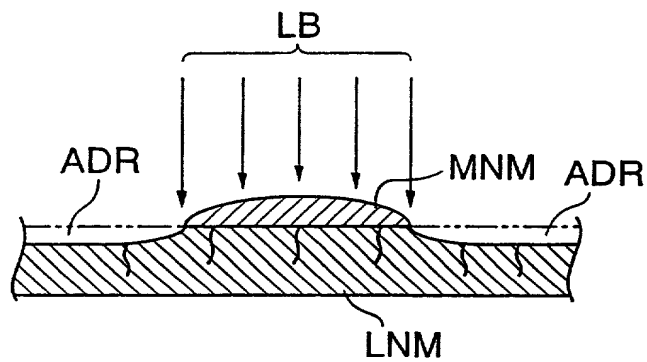
**FIG.12C**



**FIG.12D**

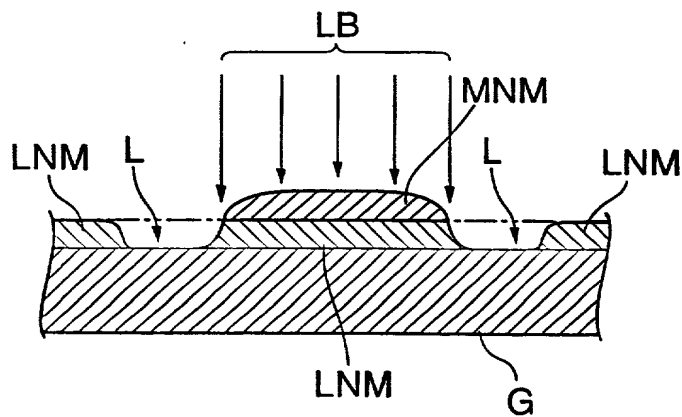


**FIG.13**



PRIOR ART

**FIG.14**



PRIOR ART